Applicant(s)/Patent Under Application/Control No. Reexamination 10/727,594 DELBREIL ET AL. Notice of References Cited **Art Unit** Examiner Page 1 of 1 2618 JOHN J. LEE **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY Eidson, Donald Brian 455/561 Α US-6,411,824 06-2002 * US-6,970,679 11-2005 Blatz et al. 455/41.1 В * US-2002/0150228 10-2002 Umeda et al. 379/220.01 С US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U V

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